Amy decided to coordinate the tour for the BGCS students who were still excited about our STEM related work at the ARC labs after participating in the BGCS Science Fair held at John F. Kennedy Middle School on July 9th. Students were able to visit the new Thin Film Deposition Lab and the Jefferson Lab Copy Center along with Surface Characterization Labs 121 and 123. Olga Trofimova demonstrated the Hirox microscope and summer interns Thomas Dushatinski and Samson Worrell demonstrated the Phenom microscope.

At the conclusion of the tour, a pizza lunch was provided for the students before they traveled back to Suffolk. Each student also received a take home bag filled with items donated by various William & Mary departments.
Daniel Iriks, an ODU/Jefferson Lab Research Experience for Undergraduates (REU) summer intern, presented his research at the Jefferson Lab Annual Summer Poster Session. His poster was titled “Automatic Surface Defect Detection in Superconducting Radio Frequency Cavities using C++ and OpenCV”. Daniel will be returning to California to attend Sonoma State University.

Melissa Meyerson, a Jefferson Lab summer intern and recent graduate of the University of Maryland, presented her summer research titled “Commissioning of Pulse Reverse Electropolishing of Niobium in an HF-Free Aqueous Electrolyte” at the Jefferson Lab Annual Summer Poster Session.
Nick Moore, Christian Worrell, Silvina Pagola (W&M Applied Science Research Scientist), and Jeffrey Jones, Silvina’s summer intern, are seen working on the Hirox.

Samson Worrell brought his nephew Christian Worrell to the lab for a visit. They are pictured here working together on the Hirox.

Cheryl Outland’s younger sister Katie came in to work for the day. She will be in 4th grade this fall and was able to learn how to operate the Phenom and take home the images she took.

Amy is pictured here with Betty Beeler, Linda Williams and Patty Hunt after the group met for lunch. Both Betty and Linda retired from Jefferson Lab and Patty is a Department of Energy employee.